

Notice of References Cited	Application/Control No. 10/533,918	Applicant(s)/Patent Under Reexamination OZAWA ET AL.	
	Examiner Nguyen T. Ha	Art Unit 2831	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,274,061	08-2001	Tamamitsu, Kenji	252/62.2
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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